

Search Notes

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Examiner

Chuck Huynh

Applicant(s)/Patent under
Reexamination

HICKS ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	9/26/2006	CH
455	466	9/27/2006	CH
709	230	9/27/2006	CH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Reveiwed Reference used	9/26/2006	CH
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